

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination LEE ET AL.	
		Examiner Dean O. Takaoka	Art Unit 2817	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gneiting, Thomas, Advanced Modeling Solution, April 2001, Agilent EEs of EDA Seminar.
	V	Cheng, Yuhua et al., High-Frequency Small Signal AC and Noise Modeling of MOSFETs for RF IC Design, March 2002, IEEE, Volume 49 No. 3.
	W	Jang, Jaejune, Small-Signal Modeling of RF CMOS, August 2004, Stanford University.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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